PH3120L

N-channel TrenchMOS logic level FET

Rev. 03 — 30 March 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Higher operating power due to low thermal resistance
- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources

1.3 Applications

- DC-to-DC convertors
- Notebook computers

- Portable equipment
- Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-------------------|-------------------------------------|---|-----|------|------|------|
| V_{DS} | drain-source voltage | T _j ≥ 25 °C; T _j ≤ 150 °C | - | - | 20 | V |
| I _D | drain current | T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u> | - | - | 100 | Α |
| P _{tot} | total power dissipation | T _{mb} = 25 °C; see <u>Figure 2</u> | - | - | 62.5 | W |
| Dynamic | characteristics | | | | | |
| Q_{GD} | gate-drain charge | $V_{GS} = 4.5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11 | - | 12.8 | - | nC |
| Static ch | aracteristics | | | | | |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{see } \frac{\text{Figure 10}}{\text{otherwise}}}$ | - | 2.25 | 2.65 | mΩ |



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Pinning information

Pinning information Table 2.

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-----------------------------------|--------------------|---|
| 1 | S | source | | _ |
| 2 | S | source | mb | D |
| 3 | S | source | | $G \stackrel{\longleftarrow}{\Longrightarrow} \stackrel{\longleftarrow}{A}$ |
| 4 | G | gate | q | <u> </u> |
| mb | D | mounting base; connected to drain | 1 2 3 4 | mbb076 S |
| | | | SOT669 (LFPAK) | |

Ordering information 3.

Table 3. **Ordering information**

| Type number | Package | | |
|-------------|---------|---|---------|
| | Name | Description | Version |
| PH3120L | LFPAK | plastic single-ended surface-mounted package (LFPAK); 4 leads | SOT669 |

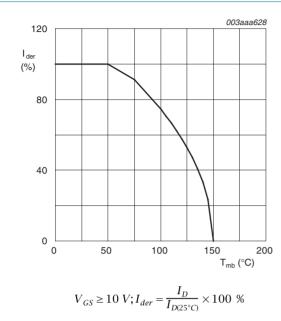
Limiting values

Limiting values Table 4.

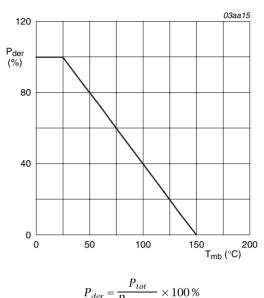
In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|----------------------|--|---|-----|------|------|
| V_{DS} | drain-source voltage | $T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$ | - | 20 | V |
| V_{GS} | gate-source voltage | | -20 | 20 | V |
| I _D | drain current | V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u> | - | 100 | Α |
| | | V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u> | - | 76 | Α |
| I _{DM} | peak drain current | $t_p \le 10 \mu s$; pulsed; $T_{mb} = 25 ^{\circ}C$; see Figure 3 | - | 300 | Α |
| P _{tot} | total power dissipation | T _{mb} = 25 °C; see <u>Figure 2</u> | - | 62.5 | W |
| T _{stg} | storage temperature | | -55 | 150 | °C |
| Tj | junction temperature | | -55 | 150 | °C |
| Source-dra | ain diode | | | | |
| Is | source current | $T_{mb} = 25 ^{\circ}C$ | - | 52 | Α |
| I _{SM} | peak source current | $t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$ | - | 152 | Α |
| Avalanche | ruggedness | | | | |
| E _{DS(AL)S} | non-repetitive drain-source avalanche energy | $V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C; } I_D = 46.2 \text{ A; } V_{sup} \leq 20 \text{ V;}$ unclamped; $t_p = 0.32 \text{ ms; } R_{GS} = 50 \Omega$ | - | 210 | mJ |

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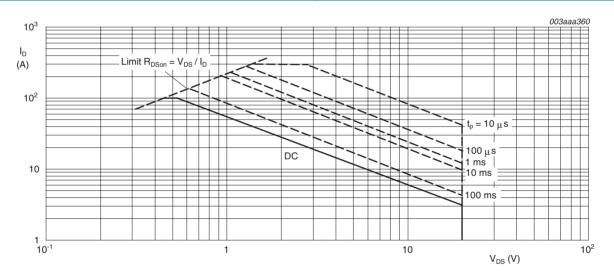


Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse; $V_{GS} = 10V$

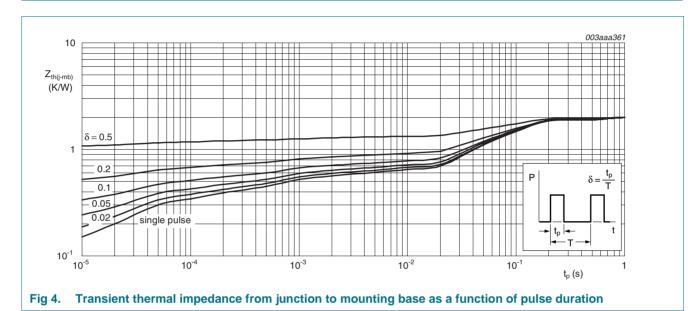
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---|--------------|-----|-----|-----|------|
| $R_{th(j\text{-}mb)}$ | thermal resistance from junction to mounting base | see Figure 4 | - | - | 2 | K/W |



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6. Characteristics

Table 6. Characteristics

| Table 6. | Characteristics | | | | | |
|----------------------|-----------------------------------|--|------|------|---|------|
| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
| Static cha | racteristics | | | | | |
| V _{(BR)DSS} | drain-source breakdown voltage | $I_D = 10 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | 20 | - | - | V |
| $V_{GS(th)}$ | gate-source threshold voltage | $I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u> | 0.65 | - | - | V |
| | | $I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u> | 1 | 1.5 | 2 | V |
| I _{DSS} | drain leakage current | $V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$ | - | - | 500 | μΑ |
| | | $V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 0.06 | 1 | μΑ |
| I _{GSS} | gate leakage current | $V_{GS} = 15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$ | - | 2 | 100 | nA |
| | | V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C | - | 2 | 100 | nA |
| R _{DSon} | drain-source on-state resistance | $V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see <u>Figure 9</u> ; see <u>Figure 10</u> | - | 2.25 | 2 500 3 1 100 100 5 2.65 6.3 3.7 | mΩ |
| | | $V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 150 °C;$ see <u>Figure 9</u> ; see <u>Figure 10</u> | - | 5.1 | | mΩ |
| | | $V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9; see Figure 10 | - | 3 | | mΩ |
| Dynamic | characteristics | | | | | |
| Q _{G(tot)} | total gate charge | $I_D = 50 \text{ A}; V_{DS} = 10 \text{ V}; V_{GS} = 4.5 \text{ V};$ | - | 48.5 | - | nC |
| Q_{GS} | gate-source charge | T _j = 25 °C; see <u>Figure 11</u> | - | 12.7 | - | nC |
| Q_{GD} | gate-drain charge | | - | 12.8 | - | nC |
| C _{iss} | input capacitance | $V_{DS} = 10 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ | - | 4457 | - | pF |
| C _{oss} | output capacitance | T _j = 25 °C; see <u>Figure 12</u> | - | 1480 | - | pF |
| C _{rss} | reverse transfer capacitance | | - | 940 | - | pF |
| d(on) | turn-on delay time | $V_{DS} = 10 \text{ V}; R_L = 0.4 \Omega; V_{GS} = 4.5 \text{ V};$ | - | 34 | - | ns |
| t _r | rise time | $R_{G(ext)} = 4.7 \Omega$; $T_j = 25 °C$; $I_D = 25 A$ | - | 90 | - | ns |
| t _{d(off)} | turn-off delay time | | - | 114 | - | ns |
| t _f | fall time | | - | 88 | - | ns |
| Source-di | rain diode | | | | | |
| V_{SD} | source-drain voltage | $I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 13 | - | 0.77 | 1.2 | V |
| t _{rr} | reverse recovery time | $I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$; $V_{DS} = 20 \text{ V}$; $T_i = 25 \text{ °C}$ | - | 63 | - | ns |

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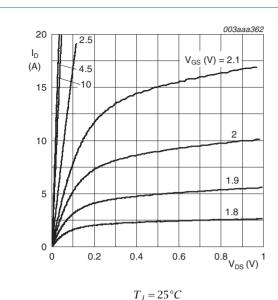
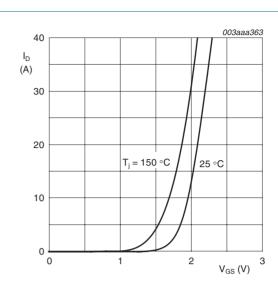
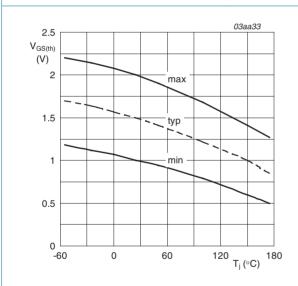


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



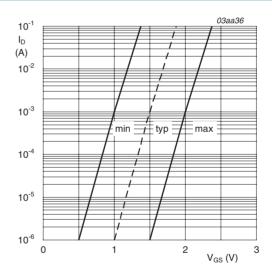
$$T_j = 25$$
° C and 150 ° C ; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 7. Gate-source threshold voltage as a function of junction temperature



 $T_i = 25 \,^{\circ}C; V_{DS} = V_{GS}$

Fig 8. Sub-threshold drain current as a function of gate-source voltage

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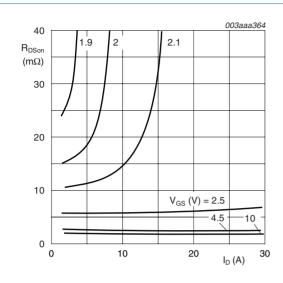


Fig 9. Drain-source on-state resistance as a function of drain current; typical values

 $T_i = 25^{\circ}C$

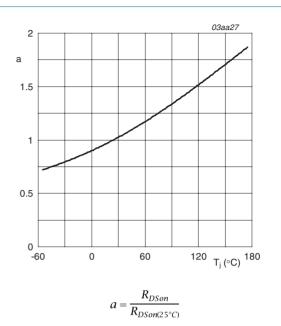


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature

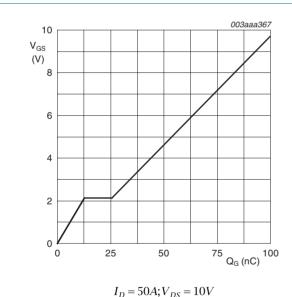
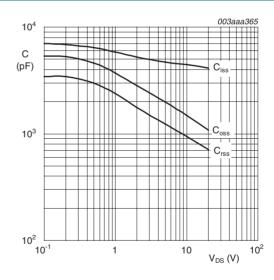


Fig 11. Gate-source voltage as a function of gate charge; typical values



 $V_{\it GS} = 0V; f = 1MHz$ 12. Input, output and reverse transfer of

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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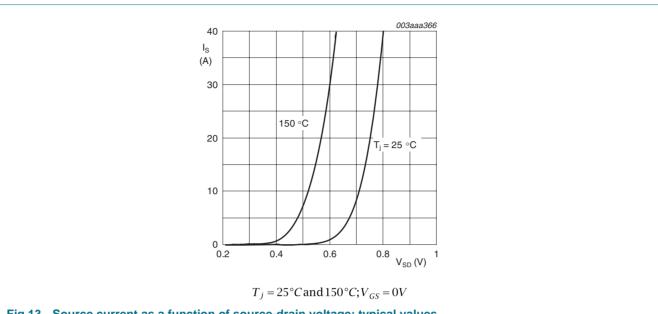
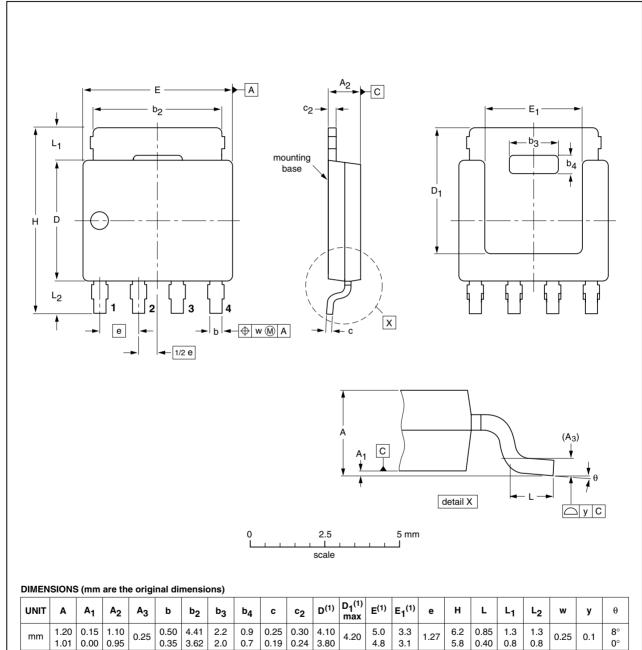


Fig 13. Source current as a function of source-drain voltage; typical values

7. Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

| OUTLINE VERSION | | | REFER | ENCES | EUROPEAN | ISSUE DATE |
|--------------------|--------|-----|--------|-------|------------|---------------------------------|
| | | IEC | JEDEC | JEITA | PROJECTION | ISSUE DATE |
| | SOT669 | | MO-235 | | | 04-10-13 06-03-16 |

Fig 14. Package outline SOT669 (LFPAK)

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Revision history

Table 7. **Revision history**

Product data sheet

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|-----------------------------|-------------------------------|--|--------------------|--------------------|
| PH3120L_3 | 20090330 | Product data sheet | - | PH3120L_2 |
| Modifications: | guideline | at of this data sheet has been sof NXP Semiconductors. | · · | |
| | Legal tex | ts have been adapted to the | e new company name | where appropriate. |
| PH3120L_2 (9397 750 14089) | 20050120 | Product data sheet | - | PH3120L-01 |
| PH3120L-01 (9397 750 12812) | 20040304 | Preliminary data sheet | - | - |

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9. Legal information

9.1 Data sheet status

| Document status [1][2] | Product status[3] | Definition |
|--------------------------------|-------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

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- [2] The term 'short data sheet' is explained in section "Definitions"
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